

FAST - (09703845.wsp.1)

File View Edit Tools Window Help

**Drafts**

- BRS: 8 and
- Pending
- Active
  - L1: (9275) 324/769,765,767,158.1.ccls.
  - L2: (37) ((determin\$4 or measur\$4) near5 capac
  - L3: (5) 1 and 2
  - L4: (2069) 257/48,268,335.ccls.
  - L5: (1) 2 and 4
  - L6: (5798) 365/174,149.ccls.
  - L7: (0) 2 and 6
- Failed
- Saved
  - S1: (4) (("6069485") or ("5904490")).PN.
  - S2: (2) ("5610104").PN.
  - S3: (23044) transistor near2 structure
  - S4: (11021) transistor adj structure
  - S5: (6868) (transistor adj structure) and "257"
  - S6: (118) (base with gate with drain) with insu
  - S7: (13) ((transistor adj structure) and "257")
  - S8: (350) 324/769.ccls.
  - S9: (4) 324/769.ccls. and (determin\$4 near5 cap
  - S10: (4) ("5304925" | "5493231" | "5493238" | "
  - S11: (3) ("5194923" | "5268318" | "5600578").PN
  - S12: (371) (determin\$4 near5 capacitance) same
  - S13: (14) ((determin\$4 near5 capacitance) same

DB: US-PG-PUB US-PAT EPO JPO DERWENT IBM TOB

Default operator: OR

Highlight all hit terms in bold

A: BRS form A: IS&R form Image Text HTML

	U	I	Document ID	Issue Dat	Pages	Title	Current OR	Current XR	Retrieval	Inventor	S	C	P	3	1
1			US 3889188	19750610	6	Time zero determination of FET reliability	324/769			Trindade; David Charles					
2			US 4448400	19840515	22	Highly scalable dynamic RAM cell with self-sign	365/185.03	257/262;		Harari; Eliyahou					
3			US 4520466	19850528	14	Dynamic random access memory	365/210	257/300;	2	Mashiko; Koichiro					
4			US 4589003	19860513	9	Solid state image sensor comprising photo	257/258	257/262;		Yamada; Hidetoshi et al.					
5			US 5365477	19941115	12	Dynamic random access memory device	365/174	257/110;		Cooper, Jr.; James A. et al.					
6			US 5753946	19980519	18	Ferroelectric memory	257/295	257/E27.10		Naiki; Ihachi et al.					
7			US 5757204	19980526	16	Method and circuit for detecting boron ("B") i	324/769	4; 257/E29		Nayak; Deepak Kumar et al.					
8			US 5821766	19981013	15	Method and apparatus for measuring the metal	324/769	257/E21.53		Kim; Sung-Ki et al.					
9			US 5835409	19981110	31	Compact page-erasable memory	365/185.15	257/209;		Lambertson; Roy et al.					

Ready